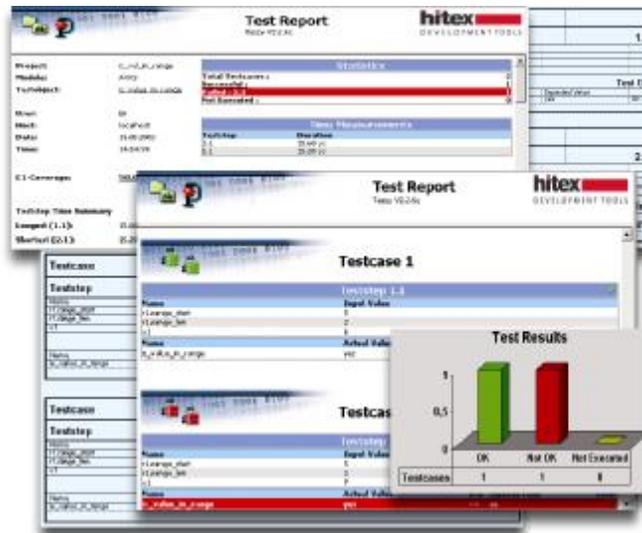


Tessy V2.2 Features

Enhanced Reports

In addition to the formats known from Tessy V2.1, test reports can now be created in word format, in HTML format with floating navigation menu and EXCEL format. The HTML and EXCEL batch reports provide further details about C1 coverage and number of failed/passed test cases for each test object.



Testing the User's Unchanged Binary

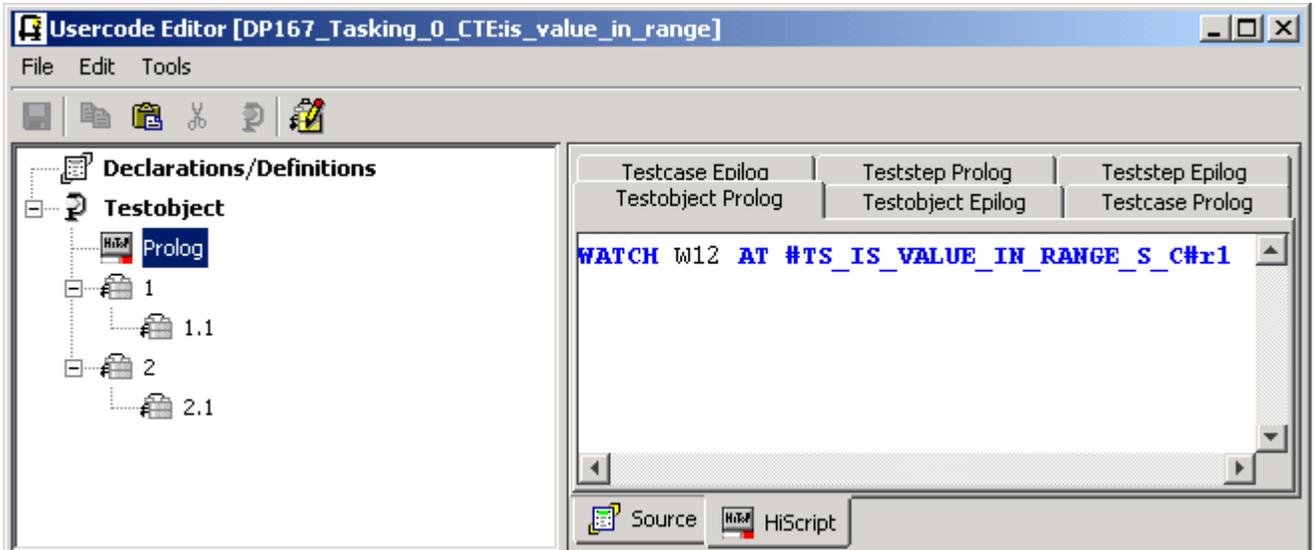
Using Hitex' in-circuit emulators, the original application can now be used for unit testing. A C function is tested at its original memory location. To accomplish this, Tessy automatically generates HiSCRIPT files to control the in-circuit emulator during test execution.

Advanced Stub Functions

An enhancement to stub functions enables the user to provide values for the parameters and the return value of a stub. The user specifies these values in the Test Data Editor, where required for each test case different values. Tessy automatically checks if the stub is called by the test object with the specified values, if not, the test fails. Tessy provides the specified return value for further processing by the test object. This reveals if the test object handles the return values correctly.

Scripting Support for Emulators

Using the Usercode Editor of Tessy, HiSCRIPT commands can be executed at various points in time during the execution of the user application. This is valuable for setting up memory areas or test object variables and controlling the in-circuit emulator for any other purpose.



Additional Microcontroller Architectures and Compilers Supported

Tessy V2.2 supports	
Manufacturer	Architecture
ARM	ARM
Fujitsu	FFMC16
Infineon	TriCore + C167
Mitsubishi	M16C
Motorola	PowerPC + 68k + HC12/08
National Semiconductor	CR16C
NEC	V850
Various manufacturers	8051 derivatives

Tessy supports compilers and debuggers from ARM, Cosmic, Fujitsu, Green Hills, IAR, Keil, Metrowerks, Microtec, National Semiconductors, Tasking, Wind River.